purpose and (2) it knows of no domestic instrument or apparatus of equivalent scientific value to the foreign instrument for the applicant's intended use.

We know of no other instrument or apparatus of equivalent scientific value to the foreign instrument which is being manufactured in the United States.

Gerald A. Zerdy,

Program ManagerStatutory Import Programs Staff.

[FR Doc. E5–5895 Filed 10–24–05; 8:45 am]

BILLING CODE 3510–DS–S

DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty–Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and, Cultural Materials Importation Act of 1966 (Pub. L. 89–651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether an instrument of equivalent scientific value, for the purposes for which the instrument shown below is intended to be used, is being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, D.C. 20230. Applications may be examined between 8:30 A.M. and 5:00 P.M. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW, Washington, D.C.

Docket Number: 05–037. Applicant: California Institute of Technology, 1200 E. California Blvd., Pasadena, CA 91125. Instrument: Dual Beam SEM/FIB System, Model 200 Nanolab. Manufacturer: FEI Company, The Netherlands. Intended Use: The instrument is intended to be used to modify and analyze delicate nano–devices as well as to prepare more conventional cross-sectional thin sections for analytical electron microscopy. The nanostructures to be modified will largely be developed within Caltech's microfabrication facilitiesand the delivered software system will be re–written to enable more precise patterning and alignment of nanostructures. Metallorganic gases can be delivered to the sample surface through a gas manifold for metal deposition and etching gases can be injected to perform chemically–assisted focused ion etching. A laser interferometer stage will enable the alignment of nanostructures to existing alignment marks for a flexible nanofabrication system. A large variety of chemical analysis sensors will further extend the capabilities of the system.Application accepted by Commissioner of Customs: September 27, 2005.

Docket Number: 05–044. Applicant: Tufts University, 169 Holland Street, Somerville, MA 02144. Instrument: Low-temperature Scanning Tunneling Microscope. Manufacturer: Omicron Nanotechnology, Germany. Intended Use: The instrument is intended to be used to study molecules adsorbed on metal and semiconductor surfaces at low temperature to gain understanding of the physisorption and chemisorption processes. The research is intended to: (1) obtain high–resolution images of moleculesadsorbed on surfaces at temperatures down to 4 Kelvin, (2) record conductance and vibrational data from these systems using the microscope's spectroscopic capabilities and (3) manipulate the positions of molecules using the microscope tip. Application accepted by Commissioner of Customs: October 5, 2005.

Gerald A. Zerdy,

Program ManagerStatutory Import Programs Staff.

[FR Doc. E5–5896 Filed 10–24–05; 8:45 am]

BILLING CODE 3510–DS–S

DEPARTMENT OF COMMERCE

International Trade Administration

Princeton University, Notice of Decision on Application for Duty–Free Entry of Scientific Instrument

This decision is made pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW, Washington, D.C.

Docket Number: 05–035. Applicant: Princeton University, Princeton, New Jersey. Instrument: Geiger Mode Ionizing Counters (1350). Manufacturer: pol.hi.tech, S.R.I, Italy. Intended Use: See notice at 70 FR 48372, August 17, 2005.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as it is intended to be used, is being manufactured in the United States. Reasons: These are compatible accessories for an existing instrument. Also referred to as limited streamer tubes, they are to be interfaced to the Stanford Linear Accelerator to study all the systematics of B meson decay processes by international research projects. Extreme reliability is an essential feature, since once assembled, they cannot be removed for replacement. The only domestic assembly facility for producing large numbers of these devices (at the University of Houston) has been decommissioned. The accessories are pertinent to the intended uses and we know of no domestic accessories which can be readily adapted for this purpose. We know of no other instrument or apparatus of equivalent scientific value which is being manufactured in the United States.

Gerald A. Zerdy,

Program ManagerStatutory Import Programs Staff.

[FR Doc. E5–5894 Filed 10–24–05; 8:45 am]

BILLING CODE 3510–DS–S

DEPARTMENT OF COMMERCE

International Trade Administration

State University of New York, Stony Brook, et al., Notice of Consolidated Decision on Applications for Duty–Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Suite 4100W, Franklin Court Building, U.S. Department of Commerce, 1099 14th Street, NW, Washington, D.C.

Docket Number: 05–032. Applicant: State University of New York, Stony Brook. Instrument: Electron Microscope, Model JEM–2200FS. Manufacturer: JEOL Ltd., Japan. Intended Use: See notice at 70 FR 48372, August 17, 2005. Order Date: September 2, 2003.

Docket Number: 05–034. Applicant: The University of Southern Mississippi, Hattiesburg. Instrument: Electron Microscope, Model JEM–2100. Manufacturer: JEOL, Ltd., Japan. Intended Use:See notice at 70 FR 48372, August 17, 2005. Order Date: October 13, 2004.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United